

UV120N03L
30V 120A N-Channel Mosfet

General Description

The UV120N03L uses advanced trench technology and design to provide excellent $R_{DS(on)}$ with low gate charge.

This device is suitable for use in PWM, load switching and general purpose applications.

Features

Enhancement Mode

Very low on-resistance $R_{DS(on)}$ @ $V_{GS}=4.5V$

100% Avalanche Tested

V_{DS}	30	V
$R_{DS(on)\ TYP}@V_{GS}=10V$	2.1	$m\Omega$
$R_{DS(on)\ TYP}@V_{GS}=4.5V$	3.2	$m\Omega$
I_D	120	A

Applications

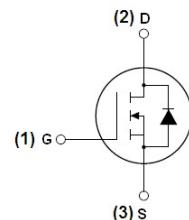
Power switching application

Hard Switched and High Frequency Circuits

Uninterruptible Power Supply



TO-252-2L Top view



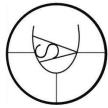
Schematic diagram

Package Marking And Ordering Information

Part ID	Package Type	Marking	Tape and Reel information
UV120N03L	TO-252-2L	UV120N03L	2500pcs/REEL

Maximum ratings, at $T_j=25^\circ C$, unless otherwise specified

Symbol	Parameter		Rating	Unit
$V_{(BR)DSS}$	Drain –Source breakdown voltage		30	V
I_S	Diode continuous forward current	$T_c=25^\circ C$	120	A
I_D	Continuous drain current @ $V_{gs}=10V$	$T_c=25^\circ C$	120	A
I_{DM}	Pulse drain current tested①	$T_c=25^\circ C$	250	A
E_{AS}	Avalanche energy, single pulsed②		85	mJ
P_D	Maximum power dissipation	$T_c=25^\circ C$	3.5	W
V_{GS}	Gate-Source voltage		± 20	V
$T_{STG}\ T_J$	Storage and operating temperature range		-55 to 175	°C



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Thermal Characteristic

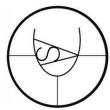
Symbol	Parameter	Typical	Unit
R_{QJC}	Thermal Resistance-Junction to Case	1.3	°C/W
R_{QJA}	Thermal Resistance-Junction to Ambient	62.5	°C/W

Typical Characteristics

Symbol	Parameter	Condition	Min	Type	Max	Unit
Static Electrical Characteristics @ $T_j=25^\circ\text{C}$ (unless otherwise stated)						
$V_{(\text{BR})DSS}$	Drain-Source Breakdown Voltage	$V_{GS}=0\text{V}$, $I_D=250\mu\text{A}$	30			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=24\text{V}$, $V_{GS}=0\text{V}$			1	μA
I_{GSS}	Gate-Body Leakage Current	$V_{GS}=\pm 20\text{V}$, $V_{DS}=0\text{V}$			± 100	nA
$V_{GS(\text{TH})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}$, $I_D=250\mu\text{A}$	1.2		2.5	V
$R_{DS(\text{ON})}$	Drain-Source On-State Resistance③	$V_{GS}=10\text{V}$, $I_D=20\text{A}$		2.1	2.5	$\text{m}\Omega$
$R_{DS(\text{ON})}$	Drain-Source On-State Resistance③	$V_{GS}=4.5\text{V}$, $I_D=10\text{A}$		3.2	3.7	$\text{m}\Omega$
Dynamic Electrical Characteristics @ $T_j=25^\circ\text{C}$ (unless otherwise stated)						
C_{iss}	Input Capacitance	$V_{DS}=20\text{V}$, $V_{GS}=0\text{V}$, $f=1\text{MHz}$		5000		PF
C_{oss}	Output Capacitance			650		PF
C_{rss}	Reverse Transfer Capacitance			500		PF
Q_g	Total Gate Charge	$V_{DS}=24\text{V}$, $I_D=30\text{A}$, $V_{GS}=10\text{V}$		104		nC
Q_{gs}	Gate-Source Charge			14		nC
Q_{gd}	Gate-Drain Charge			31		nC
Switching Characteristics						
$t_{d(on)}$	Turn-on Delay time	$V_{DD}=24\text{V}$, $I_D=8\text{A}$, $R_G=3\ \Omega$, $V_{GS}=10\text{V}$		20		nS
t_r	Turn-on Rise time			8		nS
$t_{d(off)}$	Turn-off Delay time			109		nS
t_f	Turn-off Fall time			30		nS
Source-Drain Diode Characteristics						
V_{SD}	Forward on voltage	$I_{SD}=40\text{A}$, $V_{GS}=0\text{V}$			1.2	V
t_{rr}	Reverse Recovery Time	$T_j=25^\circ\text{C}$, $I_{SD}=8\text{A}$, $V_{GS}=0\text{V}$, $dI/dt=200\text{A}/\mu\text{s}$		15		nS
Q_{rr}	Reverse Recovery Charge			34		nC

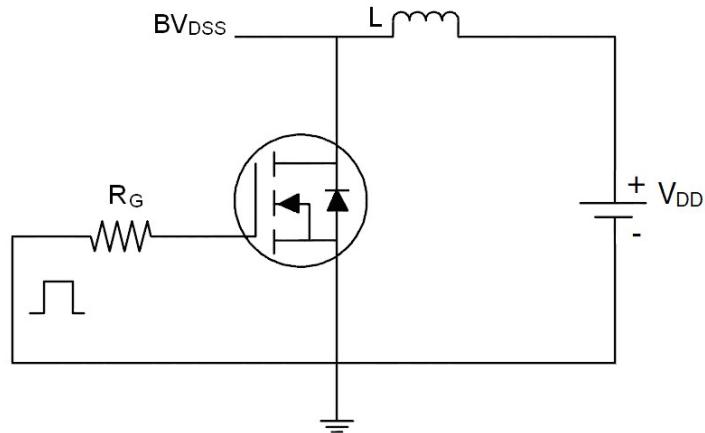
Note:

- ① Repetitive rating; pulse width limited by max, junction temperature.
- ② Limited by T_j max, starting $T_j=25^\circ\text{C}$, $L=0.1\text{mH}$, $R_G=25\ \Omega$, $I_{AS}=40\text{A}$, $V_{GS}=10\text{V}$, Part not recommended for use above this value
- ③ Pulse width $\leq 300\mu\text{s}$; duty cycle $\leq 2\%$

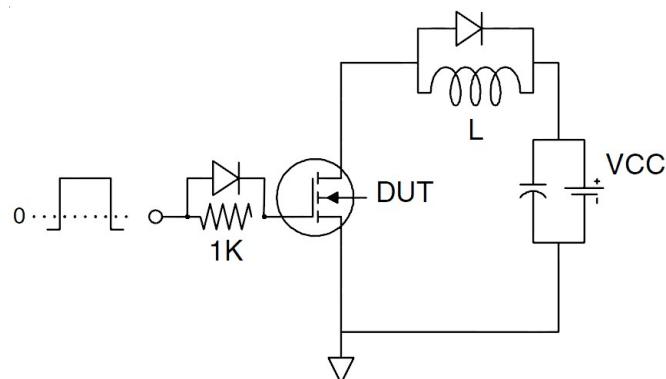


Test circuit

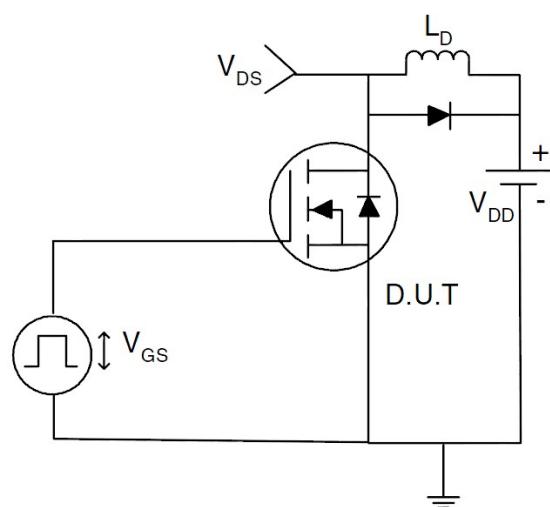
(1) E_{AS} test circuits

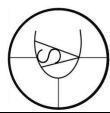


(2) Gate charge test circuit



(3) Switch time test circuit





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Fig.1 Power Dissipation

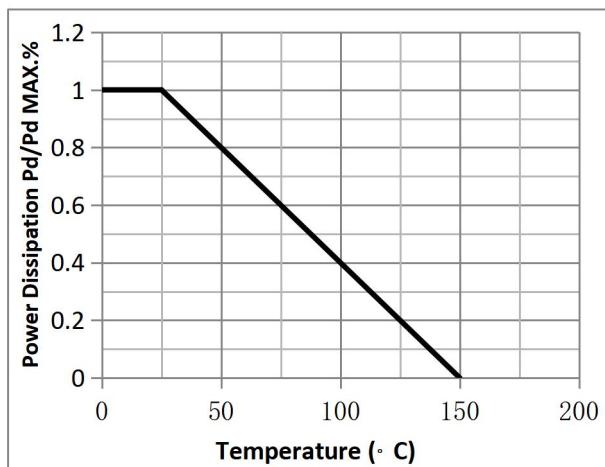


Fig.2 Typical output Characteristics

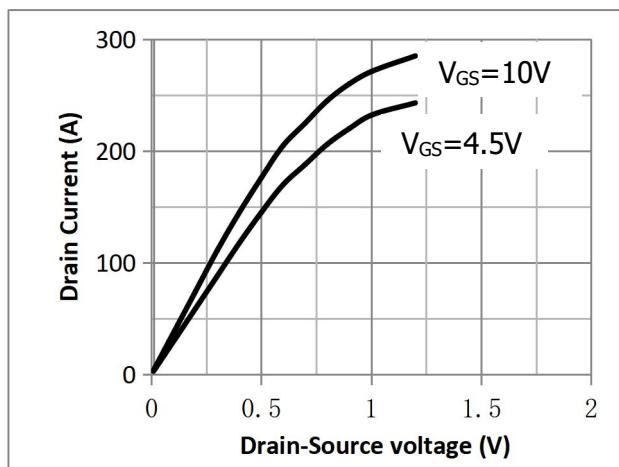


Fig.3 Threshold Voltage V.S Junction Temperature Fig.4 Resistance V.S Drain Current

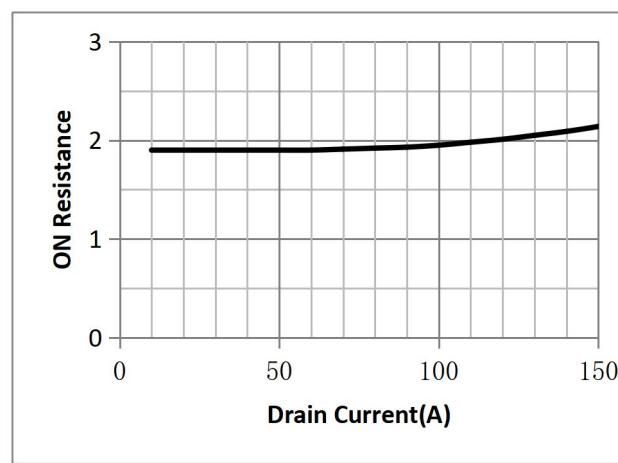
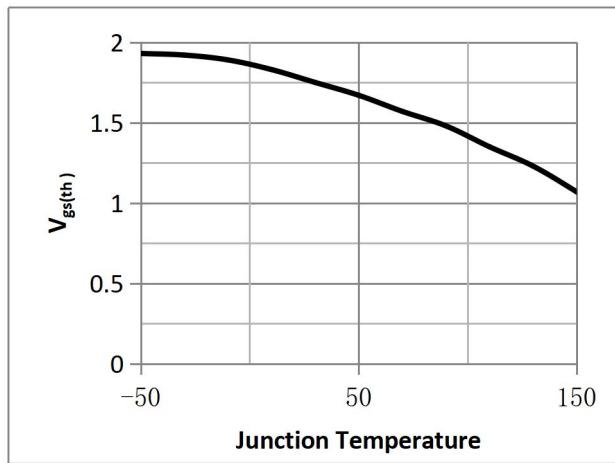


Fig.5 On-Resistance VS Gate Source Voltage

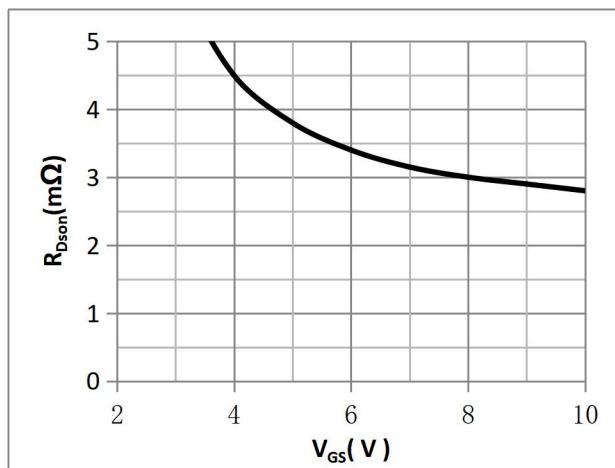
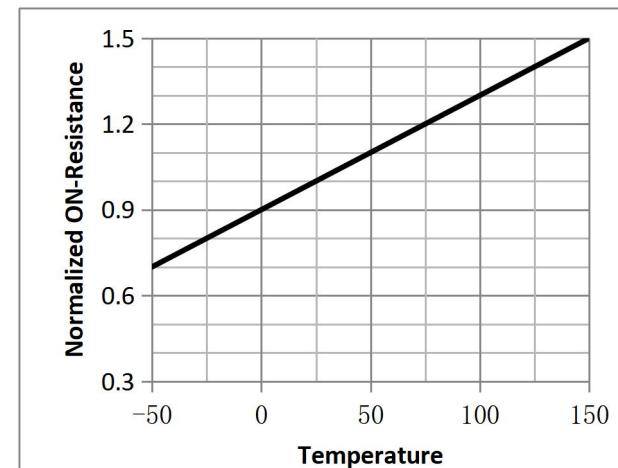
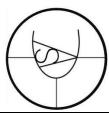


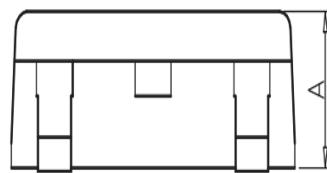
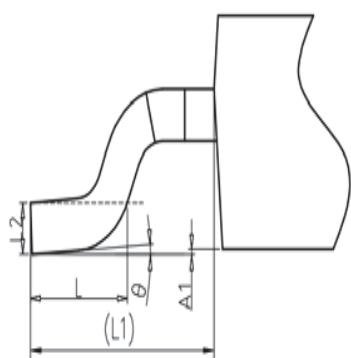
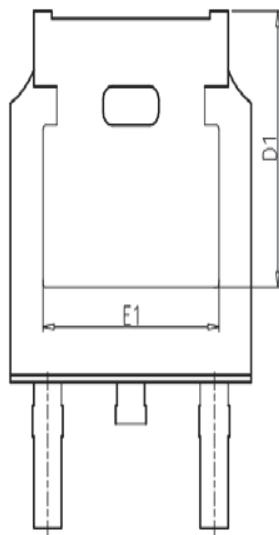
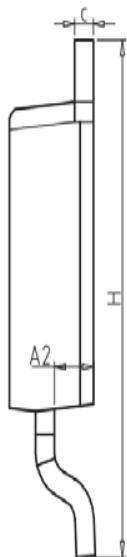
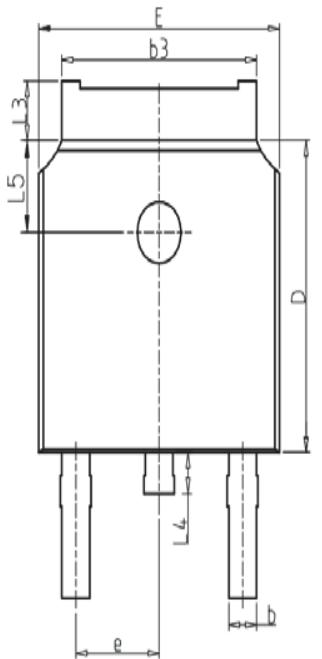
Fig.6 On-Resistance V.S Junction Temperature





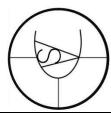
Package Information

TO-252-2L

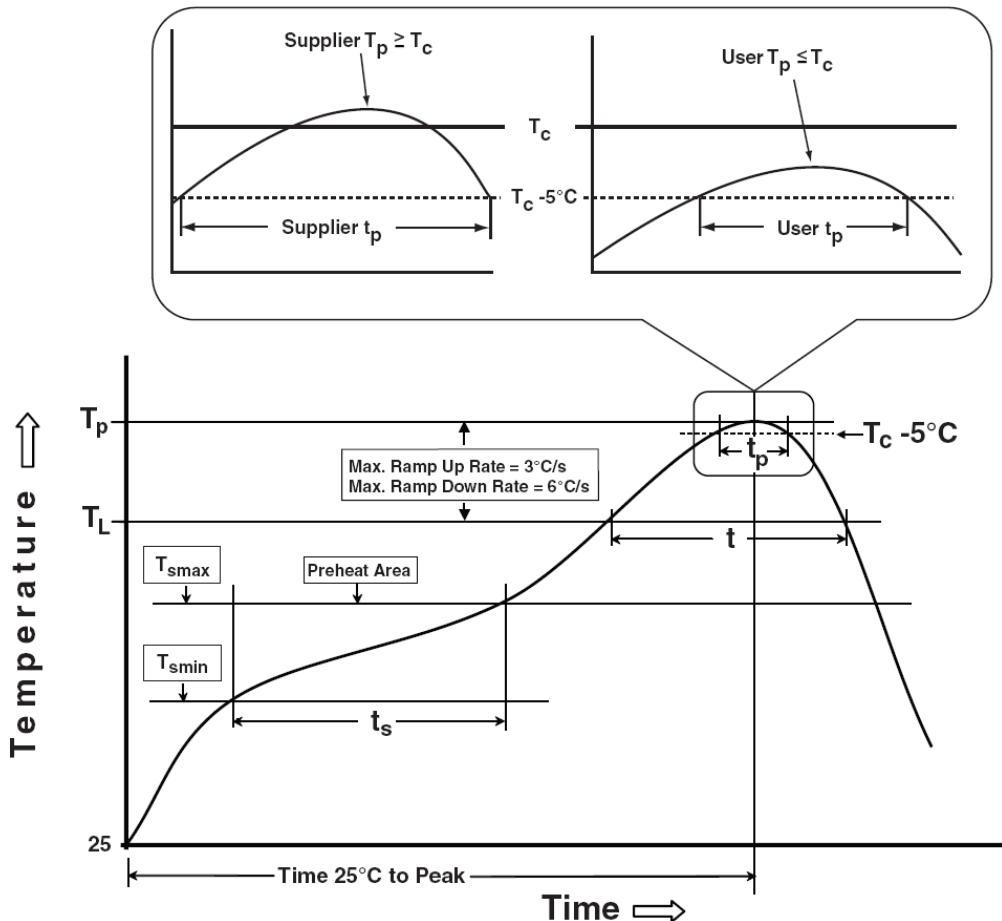


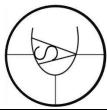
COMMON DIMENSIONS

SYMBOL	mm		
	MIN	NOM	MAX
A	2.20	2.30	2.40
A1	0.00	-	0.20
A2	0.97	1.07	1.17
b	0.68	0.78	0.90
b3	5.20	5.33	5.50
c	0.43	0.53	0.63
D	5.98	6.10	6.22
D1	5.30REF		
E	6.40	6.60	6.80
E1	4.63	-	-
e	2.286BSC		
H	9.40	10.10	10.50
L	1.38	1.50	1.75
L1	2.90REF		
L2	0.51BSC		
L3	0.88	-	1.28
L4	-	-	1.00
L5	1.65	1.80	1.95
θ	0°	-	8°



Classification Profile





Classification Reflow Profiles

Profile Feature	Sn-Pb Eutectic Assembly	Pb-Free Assembly
Preheat & Soak Temperature min (T_{smin}) Temperature max (T_{smax}) Time (T_{smin} to T_{smax}) (t_s)	100 °C 150 °C 60-120 seconds	150 °C 200 °C 60-120 seconds
Average ramp-up rate (T_{smax} to T_p)	3 °C/second max.	3°C/second max.
Liquidous temperature (T_L) Time at liquidous (t_L)	183 °C 60-150 seconds	217 °C 60-150 seconds
Peak package body Temperature (T_p)*	See Classification Temp in table 1	See Classification Temp in table 2
Time (t_p)** within 5°C of the specified classification temperature (T_c)	20** seconds	30** seconds
Average ramp-down rate (T_p to T_{smax})	6 °C/second max.	6 °C/second max.
Time 25°C to peak temperature	6 minutes max.	8 minutes max.

* Tolerance for peak profile Temperature (T_p) is defined as a supplier minimum and a user maximum.

** Tolerance for time at peak profile temperature (t_p) is defined as a supplier minimum and a user maximum.

Table 1. SnPb Eutectic Process – Classification Temperatures (T_c)

Package Thickness	Volume mm ³ <350	Volume mm ³ ≥350
<2.5 mm	235 °C	220 °C
≥2.5 mm	220 °C	220 °C

Table 2. Pb-free Process – Classification Temperatures (T_c)

Package Thickness	Volume mm ³ <350	Volume mm ³ 350-2000	Volume mm ³ >2000
<1.6 mm	260 °C	260 °C	260 °C
1.6 mm – 2.5 mm	260 °C	250 °C	245 °C
≥2.5 mm	250 °C	245 °C	245 °C

Reliability Test Program

Test item	Method	Description
SOLDERABILITY	JESD-22, B102	5 Sec, 245°C
HOLT	JESD-22, A108	168 Hrs /500 Hrs /1000 Hrs, Bias @ 150°C
PCT	JESD-22, A102	96 Hrs, 100%RH, 2atm, 121°C
TCT	JESD-22, A104	500 Cycles, -55°C~150°C